UNITRODE

Positive Floating Hot Swap Power Manager

FEATURES

- Manages Hot Swap of 15V and Above

- Precision Fault Threshold

- Programmable Average Power Limiting

- Programmable Linear Current Control

- Programmable Overcurrent Limit

- Programmable Fault Time

- Internal Charge Pump to Control External NMOS Device

- Fault Output and Catastrophic Fault Indication

- Fault Mode Programmable to Latch or Retry

- Shutdown Control

- Undervoltage Lockout

DESCRIPTION

The UCC3917 family of positive floating hot swap managers provides complete power management, hot swap, and fault handling capability. The voltage limitation of the application is only restricted by the external component voltage limitations. The IC provides its own supply voltage via a charge pump off of VOUT. The onboard 10V shunt regulator protects the IC from excess voltage. The IC also has catastrophic fault indication to alert the user that the ability to shut off the output NMOS has been bypassed. All control and housekeeping functions are integrated and externally programmable. These include the fault current level, maximum output sourcing current, maximum fault time, soft start time, and average NMOS power limiting.

The fault level across the current sense amplifier is fixed at 50mV to minimize total drop out. Once 50mV is exceeded across the current sense resistor, the fault timer will start. The maximum allowable sourcing current is programmed with a voltage divider from the VREF/$\overline{\text{CATFLT}}$ pin to generate a fixed voltage on the MAXI pin. The current level at which the output appears as a current source is equal to VMAXI divided by the current sense resistor. If desired, a controlled current startup can be programmed with a capacitor on MAXI.

When the output current is below the fault level, the output device is switched on with full gate drive. When the output current exceeds the fault level, but is less than maximum allowable sourcing level programmed by MAXI, the output remains switched on, and the fault timer starts charging CT. Once CT charges to 2.5V, the output device is turned off and attempts either a retry sometime later or waits for the state on the $\overline{\text{LATCH}}$ pin to change if in latch mode. When the output current reaches the maximum sourcing current level, the output device appears as a current source.
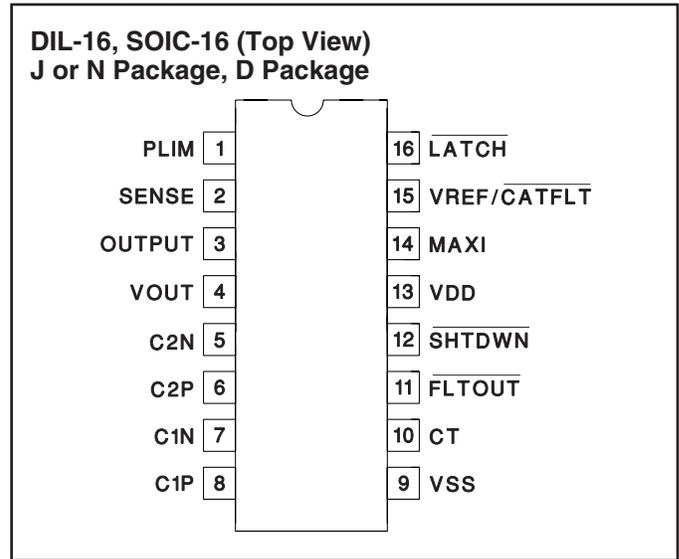
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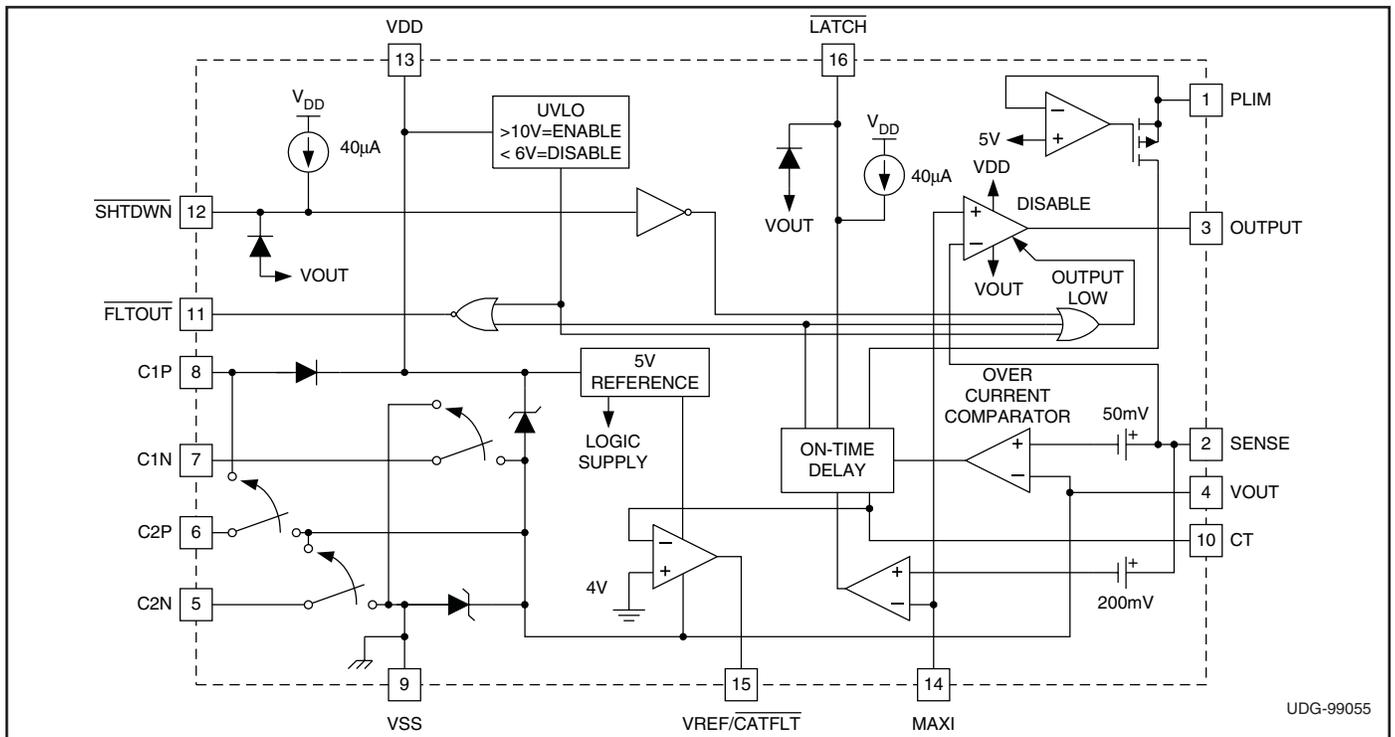
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ABSOLUTE MAXIMUM RATINGS

IDD 20mA
$\overline{\text{SHTDWN}}$ Current . . . . –500µA
LATCH Current . . . . –500µA
VREF Current . . . . –500µA
PLIM Current 10mA
MAXI Input Voltage. . . . . VDD + 0.3V
Storage Temperature . . . . –65°C to +150°C
Junction Temperature. . . . . –55°C to +150°C
Lead Temperature (Soldering, 10 sec.) . . . . +300°C
*Currents are positive into, negative out of the specified
terminal. Consult Packaging Section of Databook for thermal
limitations and considerations of package.*

CONNECTION DIAGRAM

DIL-16, SOIC-16 (Top View)
J or N Package, D Package

PLIM	1	16	$\overline{\text{LATCH}}$
SENSE	2	15	VREF/$\overline{\text{CATFLT}}$
OUTPUT	3	14	MAXI
VOUT	4	13	VDD
C2N	5	12	$\overline{\text{SHTDWN}}$
C2P	6	11	$\overline{\text{FLTOUT}}$
C1N	7	10	CT
C1P	8	9	VSS

ELECTRICAL CHARACTERISTICS:
Unless otherwise specified, T_A = 0°C to 70°C for the UCC3917, –40°C to 85° for the UCC2917 and –55°C to 125°C for the UCC1917, C_T = 4.7nF. T_A = T_J. All voltages are with respect to VOUT. Current is positive into and negative out of the specified terminal.

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
VDD Section					
I_{DD}	From VOUT (Note 1)	3.0	5	11	mA
UVLO Turn On Threshold		7.9	8.8	9.7	V
UVLO Off Voltage		5.5	6.5	7.5	V
VSS Regulator Voltage		–6	–5	–4	V
Fault Timing Section					
Overcurrent Threshold	T_A = 25°C	47.5	50	53	mV
	Over Operating Temperature	46	50	54	mV
Overcurrent Input Bias			50	500	nA
CT Charge Current	V_{CT} = 1V	–78	–50	–28	µA
CT Catastrophic Fault Threshold		3.4		4.5	V
CT Fault Threshold		2.25	2.5	2.75	V
CT Reset Threshold		0.32	0.5	0.62	V
Output Duty Cycle	Fault Condition	1.7	2.7	3.7	%
Output Section					
Output High Voltage	I_{OUT} = 0	6	8	10	V
	I_{OUT} = –500µA	5	7	9	V
Output Low Voltage	I_{OUT} = 0		0	0.05	V
	I_{OUT} = 500µA		0.1	0.5	V
	I_{OUT} = 1mA		0.5	0.9	V
Linear Current Section					
Sense Control Votlage	MAXI = 100mV	85	100	115	mV
	MAXI = 400mV	370	400	430	mV
Input Bias	MAXI = 200mV		50	500	nA
SHUTDOWN Section					
Shutdown Threshold		2.0	2.4	2.8	V
Input Current	$\overline{\text{SHTDWN}}$ = 0V	24	40	60	µA
Shutdown Delay			100	500	ns

ELECTRICAL CHARACTERISTICS: Unless otherwise specified, T_A = 0°C to 70°C for the UCC3917, –40°C to 85° for the UCC2917 and –55°C to 125°C for the UCC1917, C_T = 4.7nF. T_A = T_J. All voltages are with respect to VOUT. Current is positive into and negative out of the specified terminal.

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
LATCH Section					
Latch Threshold		1.7	2	2.3	V
Input Current	LATCH = 0V	24	40	60	µA
Fault Out Section					
Fault Output High		6	8	10	V
Fault Output Low			0.01	0.05	V
Power Limiting Section					
V$_{SENSE}$ Regulator Voltage	I_{PLIMIT} = 64µA	4.5	5	5.5	V
Duty Cycle Control	I_{PLIMIT} = 64µA	0.6	1.2	1.7	%
	I_{PLIMIT} = 1mA	0.045	0.1	0.2	%
VREF/CATFLT Section					
V$_{REF}$ Regulator Voltage		4.5	5	5.5	V
Fault Output Low	$I_{\overline{VREF/CATFLT}}$ = 5mA		0.22	0.50	V
Output Sink Current	V_{CT} = 5V, $V_{\overline{VREF/CATFLT}}$ = 5V	15	40	70	mA
Overload Comparator Threshold	Relative to MAXI	110	200	290	mV

Note 1: Set by user with R_{SS}.

PIN DESCRIPTIONS

C1N: Negative side of the upper charge pump capacitor.

C1P: Positive side of the upper charge pump capacitor.

C2N: Negative side of the lower charge pump capacitor.

C2P: Positive side of lower charge pump capacitor.

CT: A capacitor is connected to this pin to set the fault time. The fault time must be more than the time to charge the external load capacitance (see Application Information).

FLTOUT: This pin provides fault output indication. Interface to this pin is usually performed through level shift transistors. Under a non-fault condition, FLTOUT will pull to a high state. When a fault is detected by the fault timer or the under voltage lockout, this pin will drive to a low state, indicating the output NMOS is in the off state.

LATCH: Pulling this pin low causes a fault to latch until this pin is brought high or a power on reset is attempted. However, pulling this pin high before the reset time is reached will not clear the fault until the reset time is reached. Keeping LATCH high will result in normal operation of the fault timer. Users should note there will be an RC delay dependent upon the external capacitor at this pin.

MAXI: This pin programs the maximum allowable sourcing current. Since VREF/CATFLT is a regulated voltage, a voltage divider can be derived to generate the program level for MAXI. The current level at which the output appears as a current source is equal to the volt-age on MAXI divided by the current sense resistor. If desired, a controlled current start up can be programmed with a capacitor on MAXI (to VOUT), and a programmed start delay can be achieved by driving the shutdown with an open collector/drain device into an RC network.

OUTPUT: Gate drive to the NMOS pass element.

PLIM: This feature ensures that the average external NMOS power dissipation is controlled. A resistor is connected from this pin to the drain of the external NMOS pass element. When the voltage across the NMOS exceeds 5V, current will flow into PLIM which adds to the fault timer charge current, reducing the duty cycle from the 3% level.

SENSE: Input voltage from the current sense resistor. When there is greater than 50mV across this pin with respect to VOUT, a fault is sensed, and CT starts to charge.

SHTDWN: This pin provides shutdown control. Interface to this pin is usually performed through level shift transistors. When shutdown is driven low, the output disables the NMOS pass device.

VDD: Power to the I.C. Is supplied by an external current limiting resistor on initial power-up or if the load is shorted. As the load voltages rises (VOUT), a small amount of power is drawn from VOUT by an internal charge pump. The charge pump's input voltage is regulated by an on-chip 5V zener. Power to VDD is supplied

PIN DESCRIPTIONS (cont.)

by the charge pump under normal operation (i.e., external FET is on).

VOUT: Ground reference for the IC.

VREF/$\overline{CATFLT}$: This pin primarily provides an output reference for the programming of MAXI. Secondarily, it provides catastrophic fault indication. In a catastrophic fault, when the IC unsuccessfully attempts to shutdown the NMOS pass device, this pin pulls to a low state when C_T charges about the catastrophic fault thershold. A possible application for this pin is to trigger the shutdown of an auxilliaty FET in series with the main FET for redundancy.

VSS: Negative reference out of the chip. Normally current fed via a resistor to ground.

Figure 1. Fault timing circuitry for the UCC3917, including power limit and overload.

APPLICATION INFORMATION

Fault Timing

Fig. 1 shows the detailed circuitry for the fault timing function of the UCC3917. For simplicity, we first consider a typical fault mode where the overload comparator and the current source I3 do not come into play. A typical fault occurs once the voltage across the current sense resistor, R_S, exceeds 50mV. This causes the over current comparator to trip and the timing capacitor to charge with current source I1 plus the current from the power limiting amplifier, or PLIM amplifier. The PLIM amplifier is designed to only source current into the CT pin once the voltage across the output FET exceeds 5V. The current I_{PL} is related to the voltage across the FET with the following expression:

$$I_{PL} = \frac{(V_{IN} - VOUT) - 5V}{R_{PL}}$$

Note that under normal fault conditions where the output current is just above the fault level, $VOUT \cong V_{IN}$, $I_{PL} = 0$, and the C_T charging current is just I1.

During a fault, CT will charge at a rate determined by the internal charging current and the external timing capacitor, CT. Once CT charges to 2.5V, the fault comparator switches and sets the fault latch. Setting the fault latch causes both the output to switch off and the charging switch to open. CT must now discharge with current source I2 until 0.5V is reached. Once the voltage at CT reaches 0.5V, the fault latch resets (assuming $\overline{LATCH}$ is high, otherwise the fault latch will not reset until the $\overline{LATCH}$ pin is brought high or a power-on reset occurs) which re-enables the output and allows the fault circuitry to regain control of the charging switch. If a fault is still present, the overcurrent comparator will close the charging switch causing the cycle to repeat. Under a constant fault the duty cycle is given by:

APPLICATION INFORMATION (cont.)

$$\text{Duty Cycle} = \frac{I2}{I_{PL} + I1} \cong \frac{1.5\mu A}{I_{PL} + 50\mu A}$$

where I_{PL} is 0µA under normal operations (see Fig. 2).
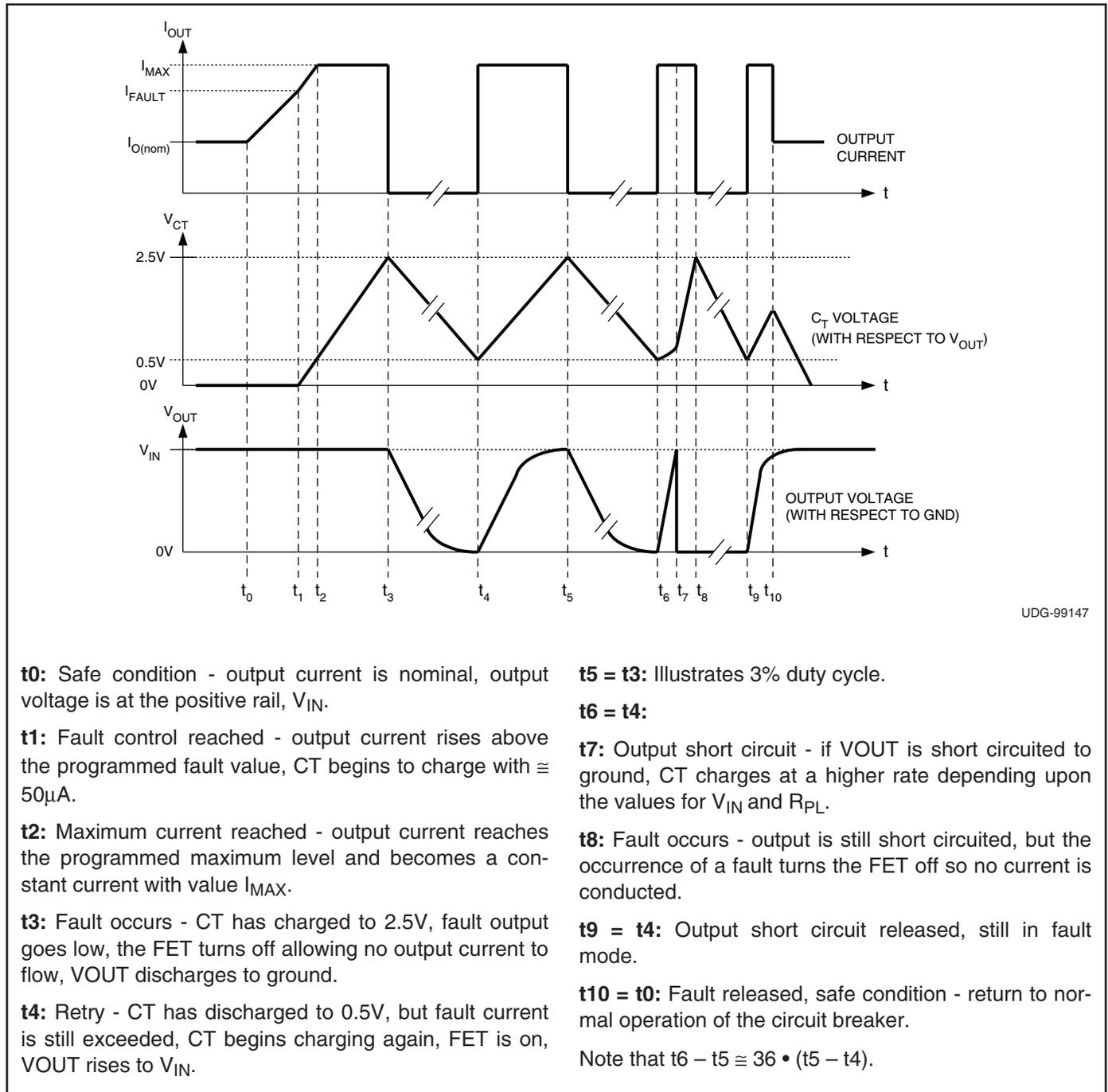
However, under large transients, average power dissipation can be limited using the PLIM pin. A proof follows, average dissipation in the pass element is given by:

$$P_{FET\ AVG} = (V_{IN} - VOUT) \bullet I_{MAX} \bullet \text{Duty Cycle}$$

$$= (V_{IN} - VOUT) \bullet I_{MAX} \bullet \frac{1.5\mu A}{I_{PL} + 50\mu A}$$

Where $(V_{IN} - VOUT) >> 5V$,

$$I_{PL} \cong \frac{V_{IN} - VOUT}{R_{PL}}$$

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t0: Safe condition - output current is nominal, output voltage is at the positive rail, V_{IN}.

t1: Fault control reached - output current rises above the programmed fault value, CT begins to charge with $\cong$ 50µA.

t2: Maximum current reached - output current reaches the programmed maximum level and becomes a constant current with value I_{MAX}.

t3: Fault occurs - CT has charged to 2.5V, fault output goes low, the FET turns off allowing no output current to flow, VOUT discharges to ground.

t4: Retry - CT has discharged to 0.5V, but fault current is still exceeded, CT begins charging again, FET is on, VOUT rises to V_{IN}.

t5 = t3: Illustrates 3% duty cycle.

t6 = t4:

t7: Output short circuit - if VOUT is short circuited to ground, CT charges at a higher rate depending upon the values for V_{IN} and R_{PL}.

t8: Fault occurs - output is still short circuited, but the occurrence of a fault turns the FET off so no current is conducted.

t9 = t4: Output short circuit released, still in fault mode.

t10 = t0: Fault released, safe condition - return to normal operation of the circuit breaker.

Note that $t6 - t5 \cong 36 \bullet (t5 - t4)$.

Figure 2. Nominal timing diagram.

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APPLICATION INFORMATION (cont.)

and where $I_{PL} \gg 50\mu A$, the duty cycle can be approximated as:

$$\frac{1.5\mu A \bullet R_{PL}}{V_{IN} - VOUT}.$$

Therefore the average power dissipation in the MOSFET can be approximated by:

$$P_{FET\ AVG} = (V_{IN} - VOUT) \bullet I_{MAX} \bullet \frac{1.5\mu A \bullet R_{PL}}{V_{IN} - VOUT}$$

$$= I_{MAX} \bullet 1.5\mu A \bullet R_{PL}$$

Notice that since $(V_{IN} - VOUT)$ cancels, average power dissipation is limited in the NMOS pass element (see Fig. 3). Also, a value for R_{PL} can be roughly determined from this approximation.

$$R_{PL} = \frac{P_{FET\ AVG}}{I_{MAX} \bullet 1.5\mu A}$$
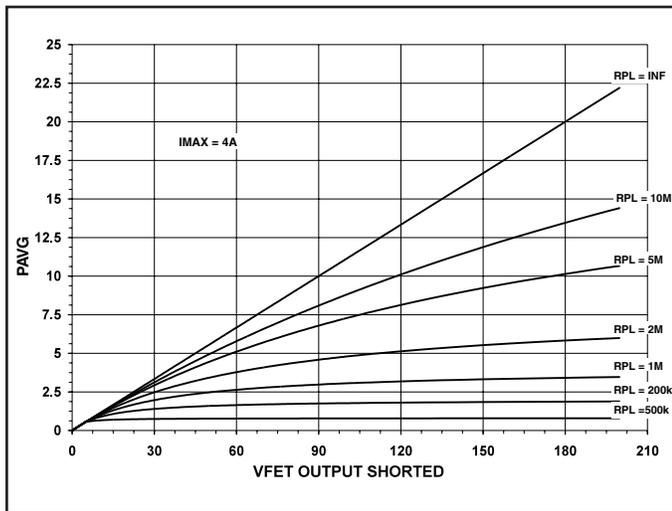
Figure 3. Plot of average power vs. FET voltage for increasing values of R_{PL}.

Overload Comparator

The overload comparator provides protection against a shorted load during normal operation when the external N-channel FET is fully enhanced. Once the FET is fully enhanced the linear current amplifier essentially saturates and the system is in effect operating open loop. Once the FET is fully enhanced the linear current amplifier requires a finite amount of time to respond to a shorted output possibly destroying the external FET. The overload comparator is provided to quickly shutdown the external MOSFET in the case of a shorted output (if the FET is fully enhanced). During an output short CT is charged by I3 at ~ 1mA. The current threshold for the overload comparator is a function of I_{MAX} and a fixed offset and is defined as:

$$I_{OVERLOAD} = I_{MAX} + 200mV / R_S$$

Once the overcurrent comparator trips the UCC3917 will enter programmed fault mode (hiccup or latched). It should be noted that on subsequent retries during Hiccup mode or if a short should occur when the UCC3917 is actively limiting the current, the output current will not exceed I_{MAX}. In the event that the external FET does not respond during a fault the UCC3917 will set the VREF/CATFLT pin low to indicate a catastrophic failure.

Selecting the Minimum Timing Capacitance

To ensure that the IC will startup correctly the designer must ensure that the fault time programmed by CT exceeds the startup time of the load. The startup time (T_{START}) is a function of several components; load resistance and load capacitance, soft start components R1, R2 and C_{SS}, the power limit current contribution determined by R_{PL}, and C_{IN}.

For a parallel capacitor-constant current load: (1)

$$T_{START} = \frac{C_{LOAD} \bullet VIN}{I_{MAX} - I_{LOAD}}$$

For a parallel R-C load :

$$T_{START} = \qquad\qquad\qquad\qquad\qquad\qquad (2)$$

$$-R_{LOAD} \bullet C_{LOAD} \bullet \ell n \left[1 - \frac{V_{IN}}{I_{MAX} \bullet R_{LOAD}} \right]$$

If the power limit function is not be used then CT(min) can be easily found:

$$CT(\min) = \frac{I_{CH} \bullet T_{START}}{dV_{CT}} \qquad\qquad (3)$$

where dV_{CT} is the hysteresis on the fault detection circuitry. During operation in the latched fault mode configuration dVCT = 2.5V. When the UCC3917 is configured for the hiccup or retry mode of fault operation dV_{CT}=2.0V.

If the power limit function is used the CT charging current becomes a function of $I_{CH} + I_{PL}$. And CT(min) is found from:
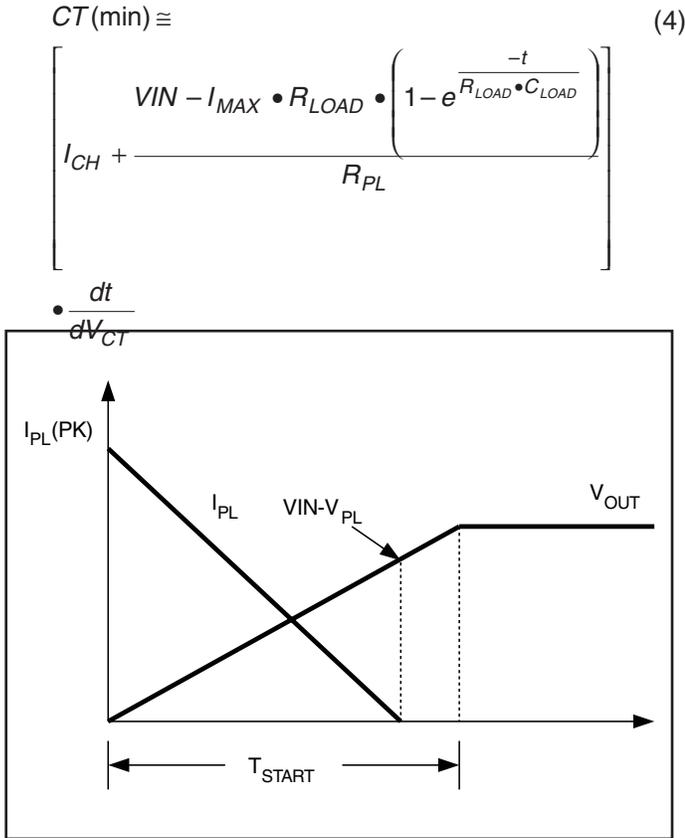
APPLICATION INFORMATION (cont.)

$$CT(min) \cong \qquad (4)$$

$$\left[I_{CH} + \frac{VIN - I_{MAX} \bullet R_{LOAD} \bullet \left(1 - e^{\frac{-t}{R_{LOAD} \bullet C_{LOAD}}} \right)}{R_{PL}} \right]$$

$$\bullet \frac{dt}{dV_{CT}}$$

Figure 4. Relationship between I_{PL}, V_{OUT} and T_{START}.

Since I_{PL} is a function of the output voltage, V_{OUT}, which varies over time, equation 4 must be integrated to solve for CT(min). However equation 4 can be easily approximated if the output voltage slews. If the output voltage slews linearly then the CT charge current contribution from the power limit circuitry is shown to be at a peak when V_{OUT} = 0V and at 0A when V_{OUT}=VIN-V_{PL}, where V_{PL} is the power limit voltage threshold. I_{PL} is shown in Fig. 4 below.

Where I_{PL} is defined as:

$$I_{PL} \equiv \frac{(VIN - V_{OUT} - V_{PL})}{R_{PL}} \qquad (5)$$

The average I_{PL} current for the interval (0, T_{START}) from Fig. 4 is defined as:

$$I_{PL}(AVG) \equiv \frac{(VIN - V_{PL})^2}{2 \bullet R_{PL} \bullet VIN} \qquad (6)$$

Equation 4 can now be simplified to:

$$CT(min) \cong \frac{I_{CH} + I_{PL}(AVG)}{dV_{CT}} \bullet T_{START} \qquad (7)$$

threshold current 60µA. For example, if the minimum when operating into a short is defined by:

$$T(on) = \frac{CT \bullet dV_{CT}}{I_{CH} + I_{PL}(pk)} \quad seconds \qquad (8)$$

where dV$_{CT}$ ~2.0V and

$$I_{PL}(pk) = \frac{VIN}{R_{PL}} \quad A \qquad (9)$$

Selecting Other External Components

Other external components are necessary for correct operation of the IC. Referring to the application diagram at the back of the data sheet, resistors R_{SENSE}, R_{SS}, R1, R2 and R3 are required and follow certain equations with a brief description following where applicable:

$$R_{SENSE} = \frac{50mV}{I_{FAULT}} \text{ (Sense Resistor)}$$

$$R_{SS} = \frac{V_{IN} - 5V}{5mA} \text{ (Connected between VSS and}$$

GND)

$$R3 = \frac{V_{IN} - 10}{5mA} \text{ (Used in series with a diode to}$$

connect VIN to VDD)

$$(R1 + R2) > 20k\Omega \text{ (Current limit out of VREF)}$$

Lastly, the external capacitors used for the charge pump are required and need to equal 0.1µF, i.e. C_{IN} = CH = C1 = C2 = 0.1µF.

### LEVEL Shift Circuitry (Optional)

The UCC3917 can be used in many systems without logic command or diagnostic feedback. If a system requires control from low-voltage logic or feedback to low-voltage logic, then level shifting circuits are required. The level shift circuits in Fig. 5A and Fig. 5B show ways to interface to LATCH and SHTDWN and the level shift circuits in Fig. 6 show ways of interfacing from FLTOUT to low-voltage logic.

In Fig. 5A, resistor R limits the level shift current. Select R so that the current in the level shift circuit never exceeds the absolute maximum current in the logic command inputs, 500µA. For example, if the maximum supply voltage for the system is 75V, select

$$R > \frac{75V}{500\mu A} = 150 \, k\Omega.$$

R must also be chosen so that the minimum current in the level shift circuit exceeds the worst case logic

APPLICATION INFORMATION (cont.)

(A)

(B)

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***Figure 5. Potential level shift circuitry
to interface to LATCH and SHTDWN on the***
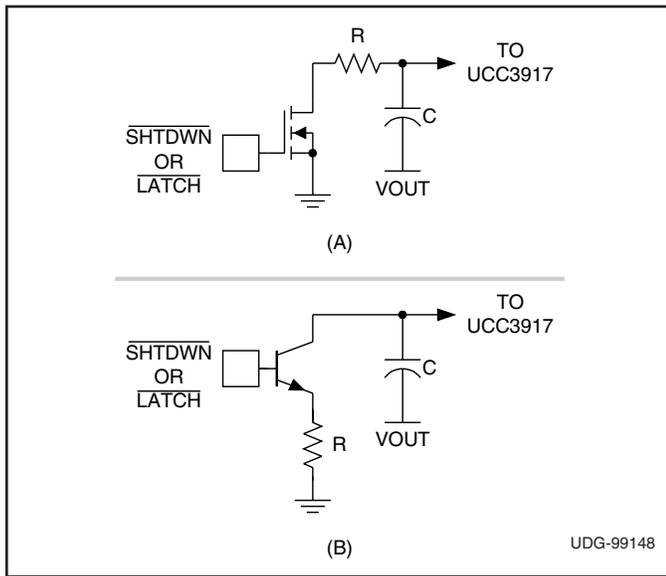
supply voltage for the system is 25V, choose

$$R > \frac{25V}{60\,\mu A} = 416\,k\,\Omega.$$

The capacitor C shown on the output of this circuit is useful to filter the level shift output and prevent false triggering from noise. The minimum recommended capacitor value is 100pF. Larger capacitors will result in better noise immunity and longer delay to logic command.

The circuit in Fig. 5B accomplished the same function as the circuit in Fig. 5A, using different components. In this circuit, select resistor R so that the transistor draws enough current to exceed the 60μA logic threshold but doesn't exceed the 500μA maximum logic input current. For example, if the input circuit is 5V logic, then
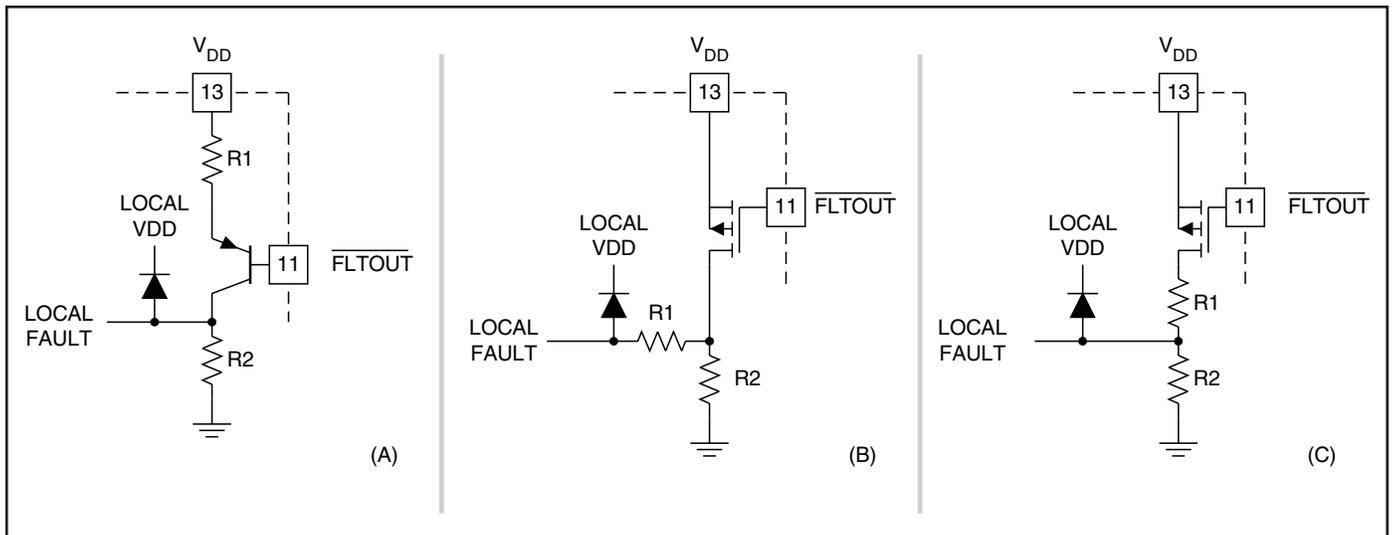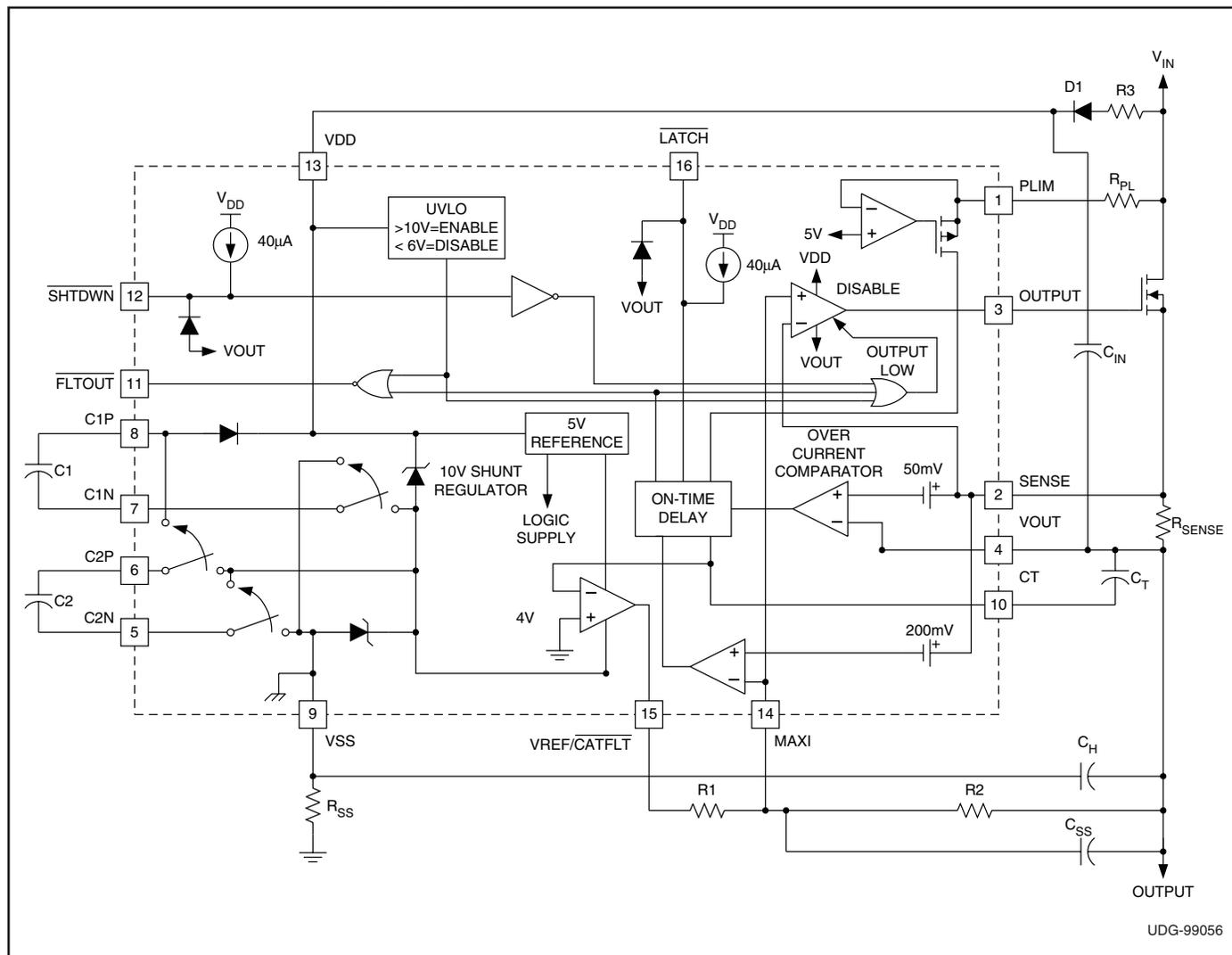

(A)

(B)

(C)

Figure 6. Potential level shift circuitry to interface to $\overline{FLTOUT}$ on the UCC3917.

APPLICATION INFORMATION (cont.)

Figure 7. Positive floating hot swap power manager UCC1917, UCC2917 and UCC3917.

SAFETY RECOMMENDATIONS

Although the UCC3917 is designed to provide system protection for all fault conditions, all integrated circuits can ultimately fail short. For this reason, if the UCC3917 is intended for use in safety critical applications where UL or some other safety rating is required, a redundant safety device such as a fuse should be placed in series with the power device. The UCC3917 will prevent the fuse from blowing for virtually all fault conditions, increasing system reliability and reducing maintenance cost, in addition to providing the hot swap benefits of the device.

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